

Features...

- High-performance, low-cost CMOS EEPROM-based programmable logic devices (PLDs) built on a Multiple Array MatriX (MAX[®]) architecture (see Table 1)
- 3.3-V in-system programmability (ISP) through the built-in IEEE Std. 1149.1 Joint Test Action Group (JTAG) interface with advanced pin-locking capability
- Built-in boundary-scan test (BST) circuitry compliant with IEEE Std. 1149.1-1990
- Enhanced ISP features:
 - Enhanced ISP algorithm for faster programming
 - ISP_Done bit to ensure complete programming
 - Pull-up resistor on I/O pins during in-system programming
- High-density PLDs ranging from 600 to 5,000 usable gates
- 4.5-ns pin-to-pin logic delays with counter frequencies of up to 227.3 MHz
- MultiVolt[™] I/O interface enabling the device core to run at 3.3 V, while I/O pins are compatible with 5.0-V, 3.3-V, and 2.5-V logic levels
- Pin counts ranging from 44 to 208 in a variety of thin quad flat pack (TQFP), plastic quad flat pack (PQFP), and plastic J-lead chip carrier (PLCC) packages
- Hot-socketing support
- Programmable interconnect array (PIA) continuous routing structure for fast, predictable performance
- PCI compatible
- Bus-friendly architecture including programmable slew-rate control
- Open-drain output option

Table 1. MAX 3000A Device Features

Feature	EPM3032A	EPM3064A	EPM3128A	EPM3256A
Usable gates	600	1,250	2,500	5,000
Macrocells	32	64	128	256
Logic array blocks	2	4	8	16
Maximum user I/O pins	34	66	96	158
t _{PD} (ns)	4.5	4.5	5.0	5.5
t _{SU} (ns)	2.9	2.8	3.3	3.9
t _{CO1} (ns)	3.0	3.1	3.4	3.5
f _{CNT} (MHz)	227.3	222.2	192.3	172.4

...and More Features

- Programmable macrocell flipflops with individual clear, preset, clock, and clock enable controls
- Programmable power-saving mode for a power reduction of over 50% in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- Programmable security bit for protection of proprietary designs
- Enhanced architectural features, including:
 - 6 pin- or logic-driven output enable signals
 - Two global clock signals with optional inversion
 - Enhanced interconnect resources for improved routability
 - Programmable output slew-rate control
- Software design support and automatic place-and-route provided by the Altera® MAX+PLUS® II development system for Windows-based PCs and Sun SPARCstations, HP 9000 Series 700/800, and IBM RISC System/6000 workstations
- Additional design entry and simulation support provided by EDIF 2.0.0 and 3.0.0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from third-party manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, Synplicity, and VeriBest
- Programming support with the Altera master programming unit (MPU), MasterBlaster™ communications cable, ByteBlasterMV™ parallel port download cable, BitBlaster™ serial download cable as well as programming hardware from third-party manufacturers and any in-circuit tester that supports Jam™ Standard Test and Programming Language (STAPL) Files (.jam), Jam STAPL Byte-Code Files (.jbc), or Serial Vector Format Files (.svf)

General Description

MAX 3000A devices are low-cost, high-performance devices based on the Altera MAX architecture. Fabricated with advanced CMOS technology, the EEPROM-based MAX 3000A devices operate with a 3.3-V supply voltage and provide 600 to 5,000 usable gates, ISP, pin-to-pin delays as fast as 4.5 ns, and counter speeds of up to 227.3 MHz. MAX 3000A devices in the -4, -5, -6, -7, and -10 speed grades are compatible with the timing requirements of the PCI Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2*. See [Table 2](#).

Device	Speed Grade				
	-4	-5	-6	-7	-10
EPM3032A	✓			✓	✓
EPM3064A	✓			✓	✓
EPM3128A		✓		✓	✓
EPM3256A		✓ (1)		✓	✓

Note:

(1) Contact Altera for up-to-date information on the availability of this speed grade.

The MAX 3000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high-density small-scale integration (SSI), medium-scale integration (MSI), and large-scale integration (LSI) logic functions. The MAX 3000A architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH, and pLSI devices. MAX 3000A devices are available in a wide range of packages, including PLCC, PQFP, and TQFP packages. See [Table 3](#).

Device	44-Pin PLCC	44-Pin TQFP	100-Pin TQFP	144-Pin TQFP	208-Pin PQFP
EPM3032A	34	34			
EPM3064A	34	34	66		
EPM3128A			80	96	
EPM3256A				116	158

Notes:

- (1) Contact Altera for up-to-date information on available device package options.
- (2) When the IEEE Std. 1149.1 (JTAG) interface is used for in-system programming or boundary-scan testing, four I/O pins become JTAG pins.

MAX 3000A devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 3000A architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

MAX 3000A devices contain 32 to 256 macrocells, combined into groups of 16 macrocells called logic array blocks (LABs). Each macrocell has a programmable-AND/fixed-OR array and a configurable register with independently programmable clock, clock enable, clear, and preset functions. To build complex logic functions, each macrocell can be supplemented with shareable expander and high-speed parallel expander product terms to provide up to 32 product terms per macrocell.

MAX 3000A devices provide programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate at 50% or lower power while adding only a nominal timing delay. MAX 3000A devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 3000A devices can be set for 2.5 V or 3.3 V, and all input pins are 2.5-V, 3.3-V, and 5.0-V tolerant, allowing MAX 3000A devices to be used in mixed-voltage systems.

MAX 3000A devices are supported by the MAX+PLUS II development system, an integrated package that offers schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The MAX+PLUS II software provides EDIF 2 0 0 and 3 0 0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The MAX+PLUS II software runs on Windows-based PCs, as well as Sun SPARCstation, HP 9000 Series 700/800, and IBM RISC System/6000 workstations.



For more information on development tools, see the [MAX+PLUS II Programmable Logic Development System & Software Data Sheet](#).

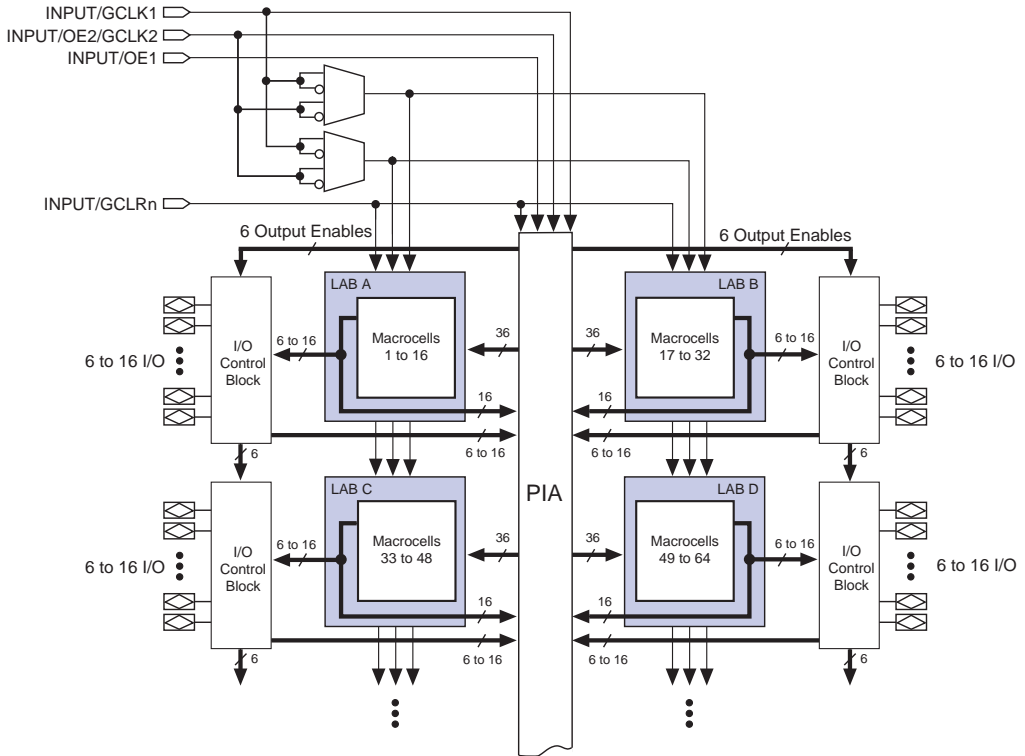
Functional Description

The MAX 3000A architecture includes the following elements:

- Logic array blocks (LABs)
- Macrocells
- Expander product terms (shareable and parallel)
- Programmable interconnect array (PIA)
- I/O control blocks

The MAX 3000A architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. [Figure 1](#) shows the architecture of MAX 3000A devices.

Figure 1. MAX 3000A Device Block Diagram



Logic Array Blocks

The MAX 3000A device architecture is based on the linking of high-performance LABs. LABs consist of 16-macrocell arrays, as shown in Figure 1. Multiple LABs are linked together via the PIA, a global bus that is fed by all dedicated input pins, I/O pins, and macrocells.

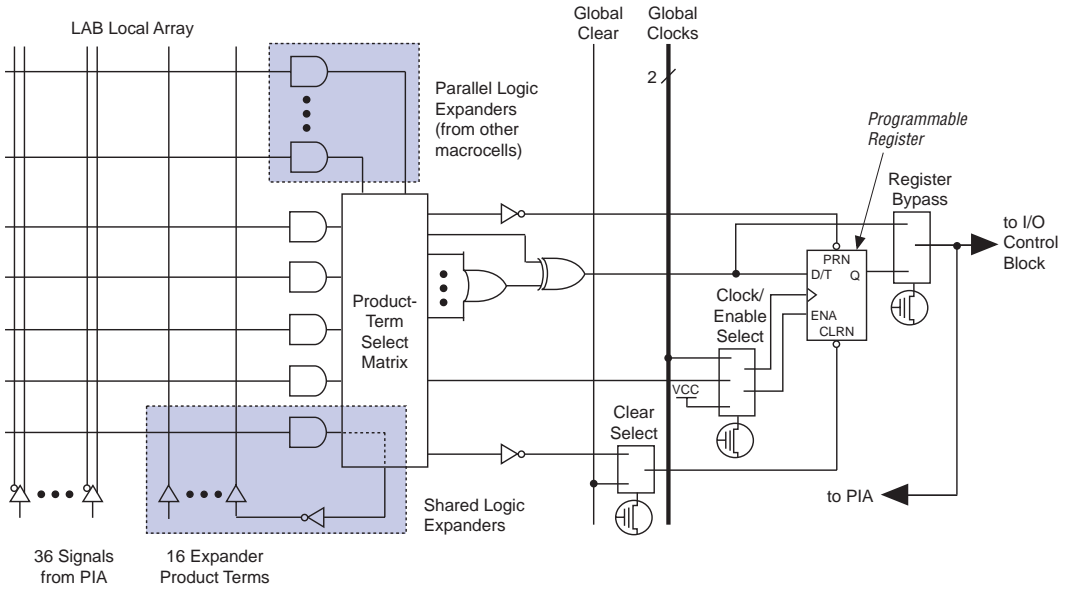
Each LAB is fed by the following signals:

- 36 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions

Macrocells

MAX 3000A macrocells can be individually configured for either sequential or combinatorial logic operation. Macrocells consist of three functional blocks: logic array, product-term select matrix, and programmable register. Figure 2 shows a MAX 3000A macrocell.

Figure 2. MAX 3000A Macrocell



Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register preset, clock, and clock ENA enable control functions.

Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The MAX+PLUS II development system automatically optimizes product-term allocation according to the logic requirements of the design.

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the MAX+PLUS II software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- Global clock signal mode, which achieves the fastest clock-to-output performance.
- Global clock signal enabled by an active-high clock enable. A clock enable is generated by a product term. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- Array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available in MAX 3000A devices. As shown in [Figure 1](#), these global clock signals can be the true or the complement of either of the two global clock pins, GCLK1 or GCLK2.

Each register also supports asynchronous preset and clear functions. As shown in [Figure 2](#), the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear from the register are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active-low dedicated global clear pin (GCLRn).

Expander Product Terms

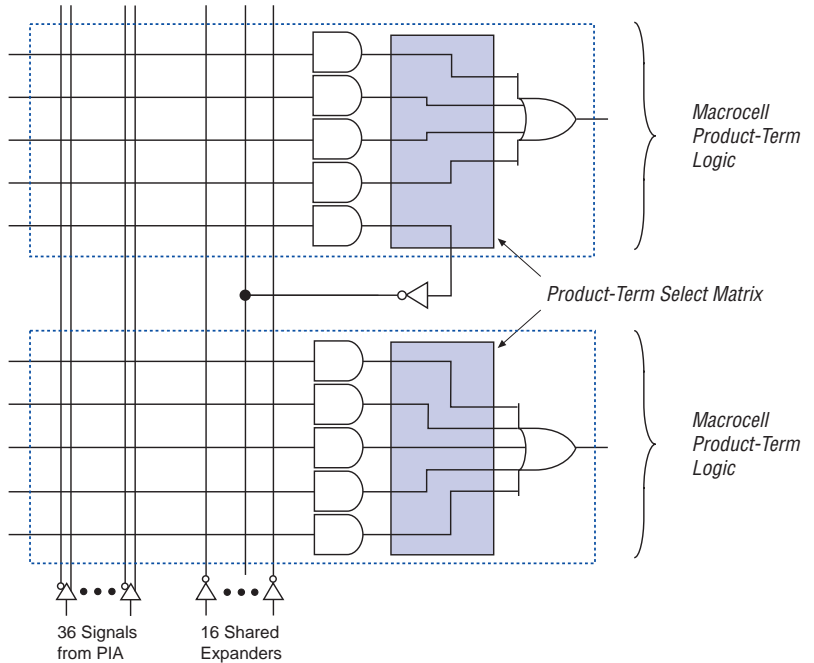
Although most logic functions can be implemented with the five product terms available in each macrocell, highly complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 3000A architecture also offers both shareable and parallel expander product terms (“expanders”) that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay (t_{SEXP}) is incurred when shareable expanders are used. [Figure 3](#) shows how shareable expanders can feed multiple macrocells.

Figure 3. MAX 3000A Shareable Expanders

Shareable expanders can be shared by any or all macrocells in an LAB.



Parallel Expanders

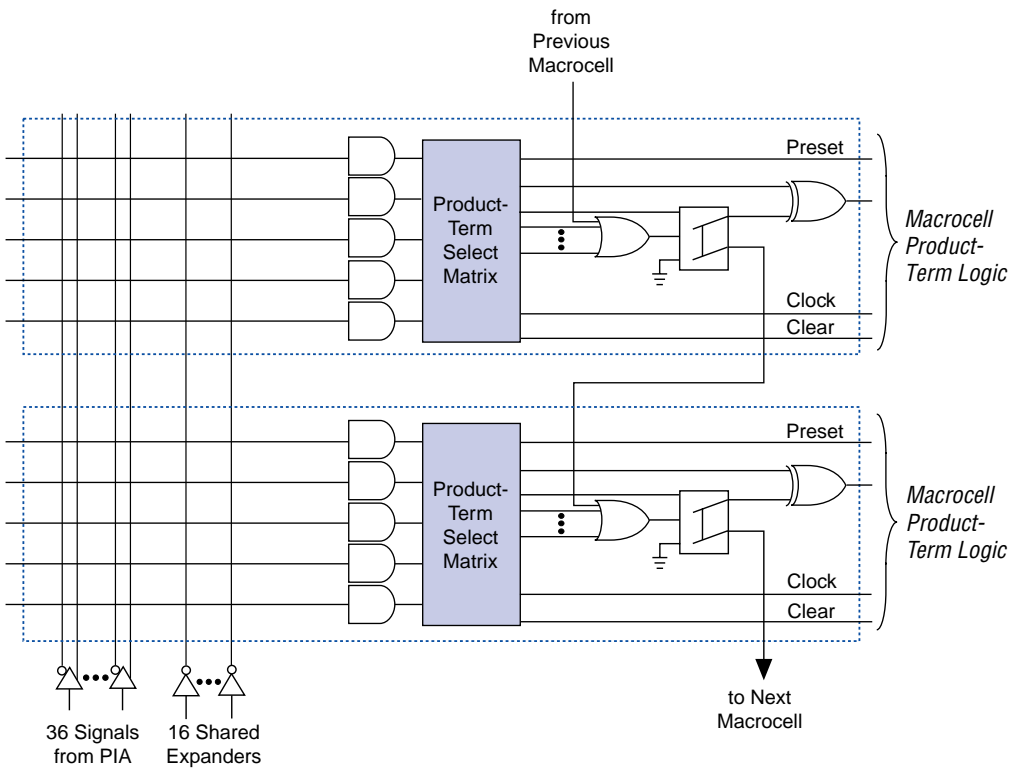
Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The MAX+PLUS II Compiler can automatically allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay (t_{PEXP}). For example, if a macrocell requires 14 product terms, the MAX+PLUS II Compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by $2 \times t_{PEXP}$.

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower-numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest-numbered macrocell can only lend parallel expanders and the highest-numbered macrocell can only borrow them. Figure 4 shows how parallel expanders can be borrowed from a neighboring macrocell.

Figure 4. MAX 3000A Parallel Expanders

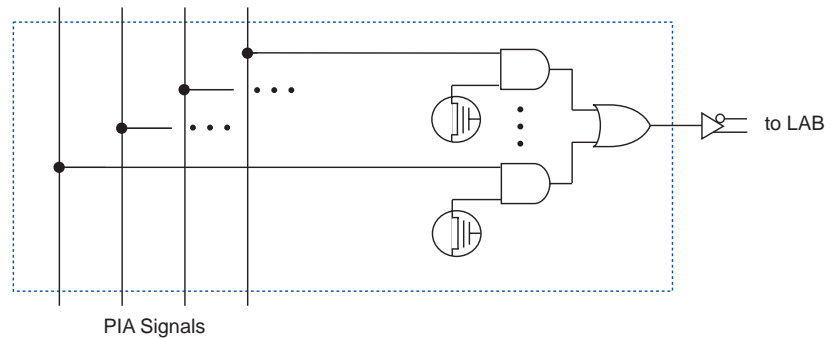
Unused product terms in a macrocell can be allocated to a neighboring macrocell.



Programmable Interconnect Array

Logic is routed between LABs on the PIA. This global bus is a programmable path that connects any signal source to any destination on the device. All MAX 3000A dedicated inputs, I/O pins, and macrocell outputs feed the PIA, which makes the signals available throughout the entire device. Only the signals required by each LAB are actually routed from the PIA into the LAB. Figure 5 shows how the PIA signals are routed into the LAB. An EEPROM cell controls one input to a 2-input AND gate, which selects a PIA signal to drive into the LAB. An EEPROM cell controls one input to a 2-input AND gate, which selects a PIA signal to drive into the LAB.

Figure 5. MAX 3000A PIA Routing

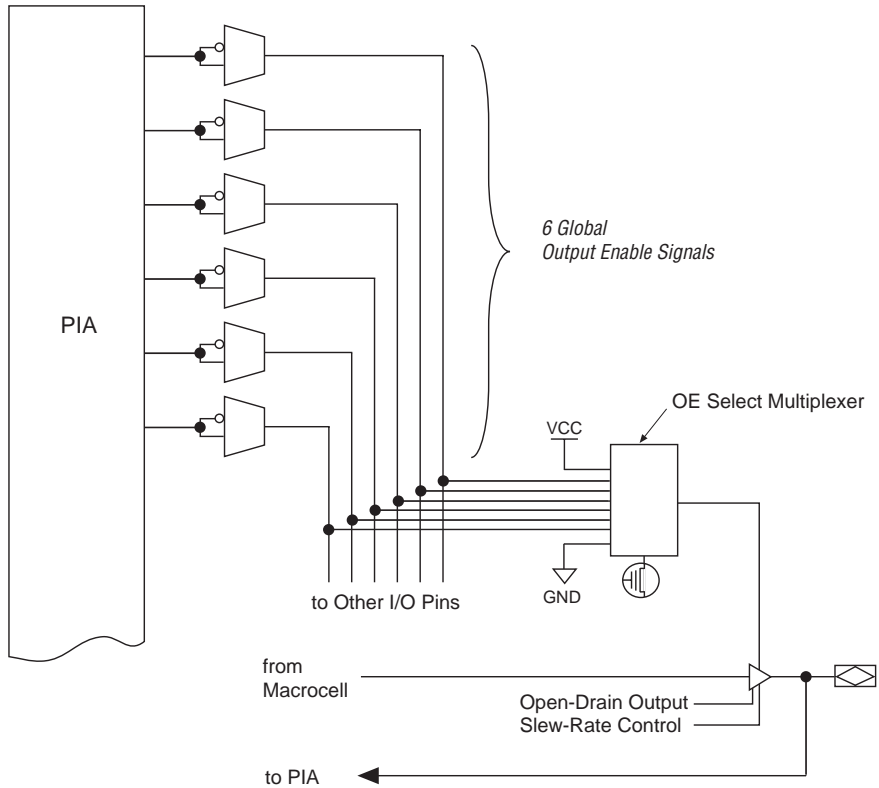


While the routing delays of channel-based routing schemes in masked or field-programmable gate arrays (FPGAs) are cumulative, variable, and path-dependent, the MAX 3000A PIA has a predictable delay. The PIA makes a design's timing performance easy to predict.

I/O Control Blocks

The I/O control block allows each I/O pin to be individually configured for input, output, or bidirectional operation. All I/O pins have a tri-state buffer that is individually controlled by one of the global output enable signals or directly connected to ground or V_{CC} . Figure 6 shows the I/O control block for MAX 3000A devices. The I/O control block has six global output enable signals that are driven by the true or complement of two output enable signals, a subset of the I/O pins, or a subset of the I/O macrocells.

Figure 6. I/O Control Block of MAX 3000A Devices



When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to V_{CC} , the output is enabled.

The MAX 3000A architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

In-System Programmability (ISP)

MAX 3000A devices can be programmed in-system via an industry-standard 4-pin IEEE Std. 1149.1-1990 (JTAG) interface. In-system programmability (ISP) offers quick, efficient iterations during design development and debugging cycles. The MAX 3000A architecture internally generates the high programming voltages required to program its EEPROM cells, allowing in-system programming with only a single 3.3-V power supply. During in-system programming, the I/O pins are tri-stated and weakly pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k Ω .

MAX 3000A devices have an enhanced ISP algorithm for faster programming. These devices also offer an ISP_Done bit that ensures safe operation when in-system programming is interrupted. This ISP_Done bit, which is the last bit programmed, prevents all I/O pins from driving until the bit is programmed.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a printed circuit board (PCB) with standard pick-and-place equipment before they are programmed. MAX 3000A devices can be programmed by downloading the information via in-circuit testers, embedded processors, the MasterBlaster communications cable, the ByteBlasterMV parallel port download cable, and the BitBlaster serial download cable. Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling. MAX 3000A devices can be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

The Jam STAPL can be used to program MAX 3000A devices with in-circuit testers, PCs, or embedded processors.



For more information on using the Jam STAPL language, see *Application Note 88 (Using the Jam Language for ISP & ICR via an Embedded Processor)* and *Application Note 122 (Using Jam STAPL for ISP & ICR via an Embedded Processor)*.

Programming with External Hardware

MAX 3000A devices can be programmed on Windows-based PCs with an Altera Logic Programmer card, MPU, and the appropriate device adapter. The MPU performs continuity checking to ensure adequate electrical contact between the adapter and the device.



For more information, see the *Altera Programming Hardware Data Sheet*.

The MAX+PLUS II software can use text- or waveform-format test vectors created with the MAX+PLUS II Text Editor or Waveform Editor to test the programmed device. For added design verification, designers can perform functional testing to compare the functional device behavior with the results of simulation.

Data I/O, BP Microsystems, and other programming hardware manufacturers also provide programming support for Altera devices.



For more information, see *Programming Hardware Manufacturers*.

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 3000A devices include the JTAG BST circuitry defined by IEEE Std. 1149.1-1990. Table 4 describes the JTAG instructions supported by MAX 3000A devices. The pin-out tables starting on page 39 of this data sheet show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Table 4. MAX 3000A JTAG Instructions

JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins
BYPASS	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation
IDCODE	Selects the IDCODE register and places it between the TDI and TDO pins, allowing the IDCODE to be serially shifted out of TDO
USERCODE	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE value to be shifted out of TDO
ISP Instructions	These instructions are used when programming MAX 3000A devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, or BitBlaster cable, or when using a Jam STAPL file, JBC file, or SVF file via an embedded processor or test equipment

The instruction register length of MAX 3000A devices is 10 bits. The IDCODE and USERCODE register length is 32 bits. Tables 5 and 6 show the boundary-scan register length and device IDCODE information for MAX 3000A devices.

Device	Boundary-Scan Register Length
EPM3032A	96
EPM3064A	192
EPM3128A	288
EPM3256A	480

Device	IDCODE (32 bits)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)	1 (1 Bit) (2)
EPM3032A	0001	0111 0000 0011 0010	00001101110	1
EPM3064A	0001	0111 0000 0110 0100	00001101110	1
EPM3128A	0001	0111 0001 0010 1000	00001101110	1
EPM3256A	0001	0111 0010 0101 0110	00001101110	1

Notes:

- (1) The most significant bit (MSB) is on the left.
 (2) The least significant bit (LSB) for all JTAG IDCODEs is 1.



See *Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices)* for more information on JTAG BST.

Figure 7 shows the timing information for the JTAG signals.

Figure 7. MAX 3000A JTAG Waveforms

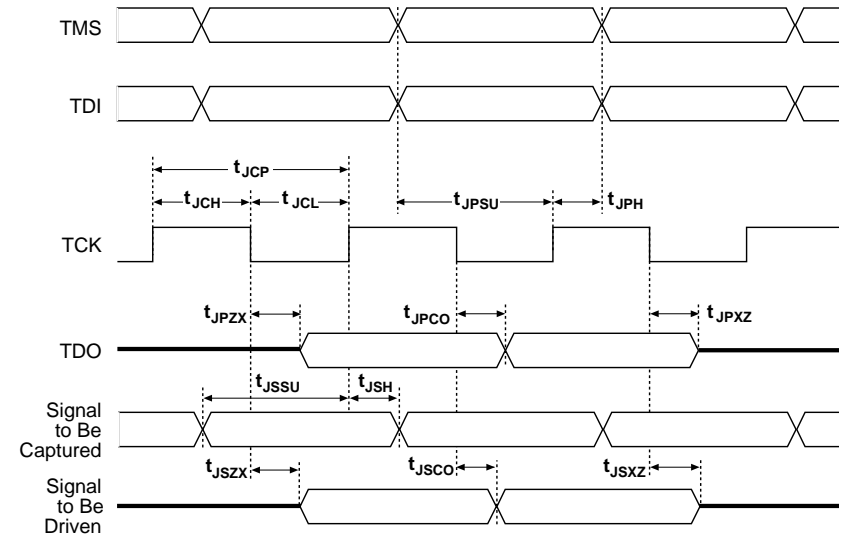


Table 7 shows the JTAG timing parameters and values for MAX 3000A devices.

Table 7. JTAG Timing Parameters & Values for MAX 3000A Devices

Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	100		ns
t_{JCH}	TCK clock high time	50		ns
t_{JCL}	TCK clock low time	50		ns
t_{JPSU}	JTAG port setup time	20		ns
t_{JPH}	JTAG port hold time	45		ns
t_{JPCO}	JTAG port clock to output		25	ns
t_{JPZX}	JTAG port high impedance to valid output		25	ns
t_{JPXZ}	JTAG port valid output to high impedance		25	ns
t_{JSSU}	Capture register setup time	20		ns
t_{JSH}	Capture register hold time	45		ns
t_{JSCO}	Update register clock to output		25	ns
t_{JSZX}	Update register high impedance to valid output		25	ns
t_{JSXZ}	Update register valid output to high impedance		25	ns

Programmable Speed/Power Control

MAX 3000A devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 3000A device for either high-speed or low-power operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the t_{LAD} , t_{LAC} , t_{IC} , t_{ACL} , t_{EN} , t_{CPW} and t_{SEXP} parameters.

Output Configuration

MAX 3000A device outputs can be programmed to meet a variety of system-level requirements.

MultiVolt I/O Interface

The MAX 3000A device architecture supports the MultiVolt I/O interface feature, which allows MAX 3000A devices to connect to systems with differing supply voltages. MAX 3000A devices in all packages can be set for 2.5-V, 3.3-V, or 5.0-V I/O pin operation. These devices have one set of V_{CC} pins for internal operation and input buffers (V_{CCINT}), and another set for I/O output drivers (V_{CCIO}).

The V_{CCIO} pins can be connected to either a 3.3-V or 2.5-V power supply, depending on the output requirements. When the V_{CCIO} pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the V_{CCIO} pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V_{CCIO} levels lower than 3.0 V incur a nominally greater timing delay of t_{OD2} instead of t_{OD1} . Inputs can always be driven by 2.5-V, 3.3-V, or 5.0-V signals.

Table 8 summarizes the MAX 3000A MultiVolt I/O support.

Table 8. MAX 3000A MultiVolt I/O Support						
V_{CCIO} Voltage	Input Signal (V)			Output Signal (V)		
	2.5	3.3	5.0	2.5	3.3	5.0
2.5	✓	✓	✓	✓		
3.3	✓	✓	✓	✓ (1)	✓	✓

Note:

- (1) When V_{CCIO} is 3.3 V, a MAX 3000A device can drive a 2.5-V device that has 3.3-V tolerant inputs.

Open-Drain Output Option

MAX 3000A devices provide an optional open-drain (equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.

Slew-Rate Control

The output buffer for each MAX 3000A I/O pin has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay of 4 to 5 ns. When the configuration cell is turned off, the slew rate is set for low-noise performance. Each I/O pin has an individual EEPROM bit that controls the slew rate, allowing designers to specify the slew rate on a pin-by-pin basis. The slew rate control affects both the rising and falling edges of the output signal.

Design Security

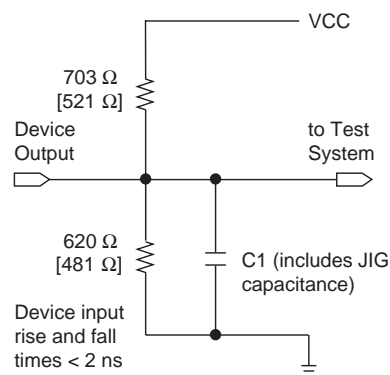
All MAX 3000A devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

Generic Testing

MAX 3000A devices are fully functionally tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in Figure 8. Test patterns can be used and then erased during early stages of the production flow.

Figure 8. MAX 3000A AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast-ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V outputs. Numbers without brackets are for 3.3-V devices or outputs.



Operating Conditions

Tables 9 through 12 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and capacitance for MAX 3000A devices.

Table 9. MAX 3000A Device Absolute Maximum Ratings Note (1)

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	Supply voltage	With respect to ground (2)	-0.5	4.6	V
V _I	DC input voltage		-2.0	5.75	V
I _{OUT}	DC output current, per pin		-25	25	mA
T _{STG}	Storage temperature	No bias	-65	150	°C
T _A	Ambient temperature	Under bias	-65	135	°C
T _J	Junction temperature	PQFP and TQFP packages, under bias		135	°C

Table 10. MAX 3000A Device Recommended Operating Conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CCINT}	Supply voltage for internal logic and input buffers		3.0	3.6	V
V _{CCIO}	Supply voltage for output drivers, 3.3-V operation		3.0	3.6	V
	Supply voltage for output drivers, 2.5-V operation		2.3	2.7	V
V _{CCISP}	Supply voltage during ISP		3.0	3.6	V
V _I	Input voltage	(3)	-0.5	5.75	V
V _O	Output voltage		0	V _{CCIO}	V
T _A	Ambient temperature	For commercial use	0	70	°C
		For industrial use	-40	85	°C
T _J	Junction temperature	For commercial use	0	90	°C
		For industrial use	-40	105	°C
t _R	Input rise time			40	ns
t _F	Input fall time			40	ns

Table 11. MAX 3000A Device DC Operating Conditions Note (4)

Symbol	Parameter	Conditions	Min	Max	Unit
V _{IH}	High-level input voltage		1.7	5.75	V
V _{IL}	Low-level input voltage		-0.5	0.8	V
V _{OH}	3.3-V high-level TTL output voltage	I _{OH} = -8 mA DC, V _{CCIO} = 3.00 V (5)	2.4		V
	3.3-V high-level CMOS output voltage	I _{OH} = -0.1 mA DC, V _{CCIO} = 3.00 V (5)	V _{CCIO} - 0.2		V
	2.5-V high-level output voltage	I _{OH} = -100 μA DC, V _{CCIO} = 2.30 V (5)	2.1		V
		I _{OH} = -1 mA DC, V _{CCIO} = 2.30 V (5)	2.0		V
		I _{OH} = -2 mA DC, V _{CCIO} = 2.30 V (5)	1.7		V
V _{OL}	3.3-V low-level TTL output voltage	I _{OL} = 8 mA DC, V _{CCIO} = 3.00 V (6)		0.4	V
	3.3-V low-level CMOS output voltage	I _{OL} = 0.1 mA DC, V _{CCIO} = 3.00 V (6)		0.2	V
	2.5-V low-level output voltage	I _{OL} = 100 μA DC, V _{CCIO} = 2.30 V (6)		0.2	V
		I _{OL} = 1 mA DC, V _{CCIO} = 2.30 V (6)		0.4	V
		I _{OL} = 2 mA DC, V _{CCIO} = 2.30 V (6)		0.7	V
I _I	Input leakage current	V _I = V _{CCINT} or ground	-10	10	μA
I _{OZ}	Tri-state output off-state current	V _O = V _{CCINT} or ground	-10	10	μA
R _{ISP}	Value of I/O pin pull-up resistor when programming in-system or during power-up	V _{CCIO} = 2.3 to 3.6 V (7)	20	74	kΩ

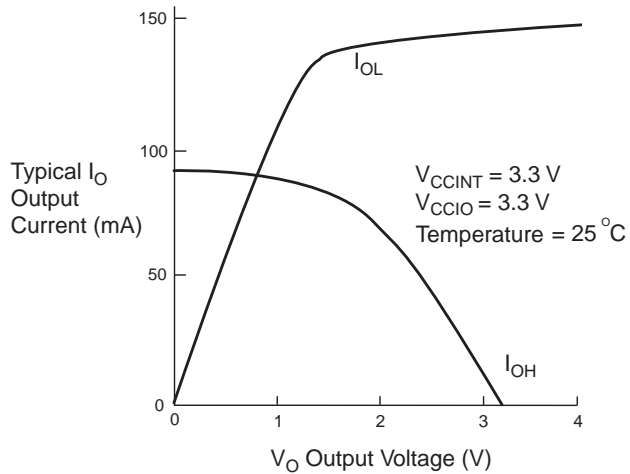
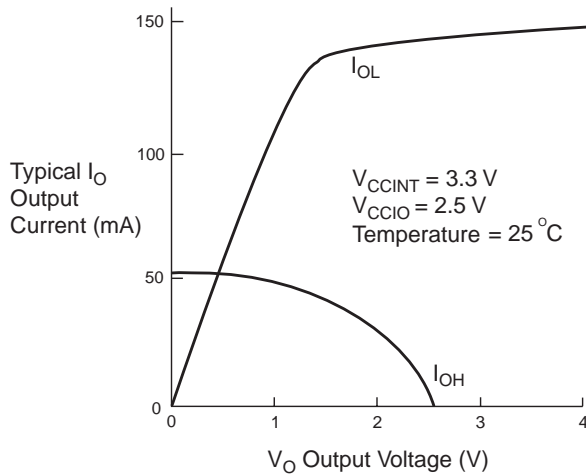
Table 12. MAX 3000A Device Capacitance Note (8)

Symbol	Parameter	Conditions	Min	Max	Unit
C _{IN}	Input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		8	pF
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		8	pF

Notes to tables:

- (1) See the *Operating Requirements for Altera Devices Data Sheet*.
- (2) Minimum DC input voltage is -0.5 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 5.75 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) All pins, including dedicated inputs, I/O pins, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.
- (4) These values are specified under the recommended operating conditions, as shown in Table 10 on page 19.
- (5) The parameter is measured with 50% of the outputs each sourcing the specified current. The I_{OH} parameter refers to high-level TTL or CMOS output current.
- (6) The parameter is measured with 50% of the outputs each sinking the specified current. The I_{OL} parameter refers to low-level TTL or CMOS output current.
- (7) This pull-up exists while devices are programmed in-system and in unprogrammed devices during power-up.
- (8) Capacitance is measured at 25° C and is sample-tested only. The OE1 pin (high-voltage pin during programming) has a maximum capacitance of 20 pF.

Figure 9 shows the typical output drive characteristics of MAX 3000A devices.

Figure 9. Output Drive Characteristics of MAX 3000A Devices**3.3 V****2.5 V**

Power Sequencing & Hot-Socketing

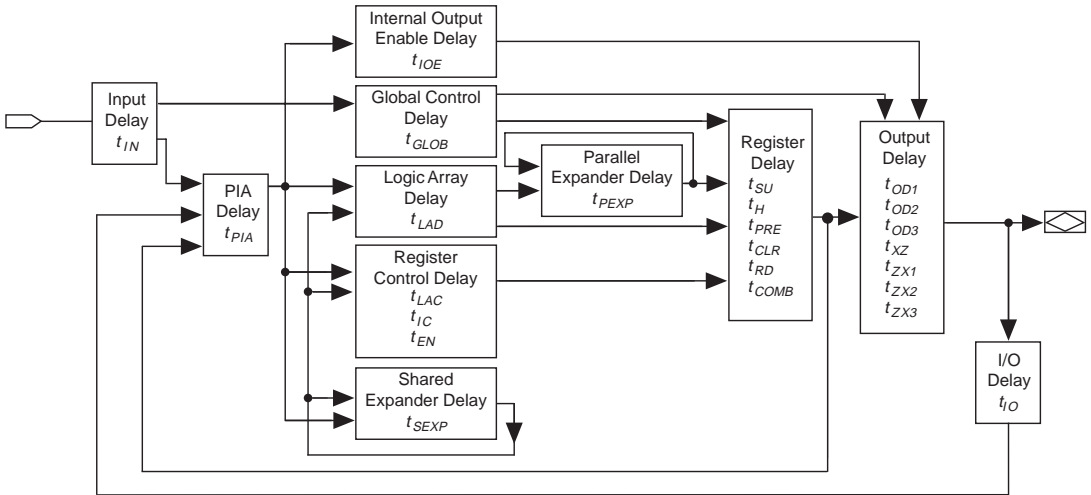
Because MAX 3000A devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. The V_{CCIO} and V_{CCINT} power planes can be powered in any order.

Signals can be driven into MAX 3000A devices before and during power-up without damaging the device. In addition, MAX 3000A devices do not drive out during power-up. Once operating conditions are reached, MAX 3000A devices operate as specified by the user.

Timing Model

MAX 3000A device timing can be analyzed with the MAX+PLUS II software, with a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 10. MAX 3000A devices have predictable internal delays that enable the designer to determine the worst-case timing of any design. The software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for device-wide performance evaluation.

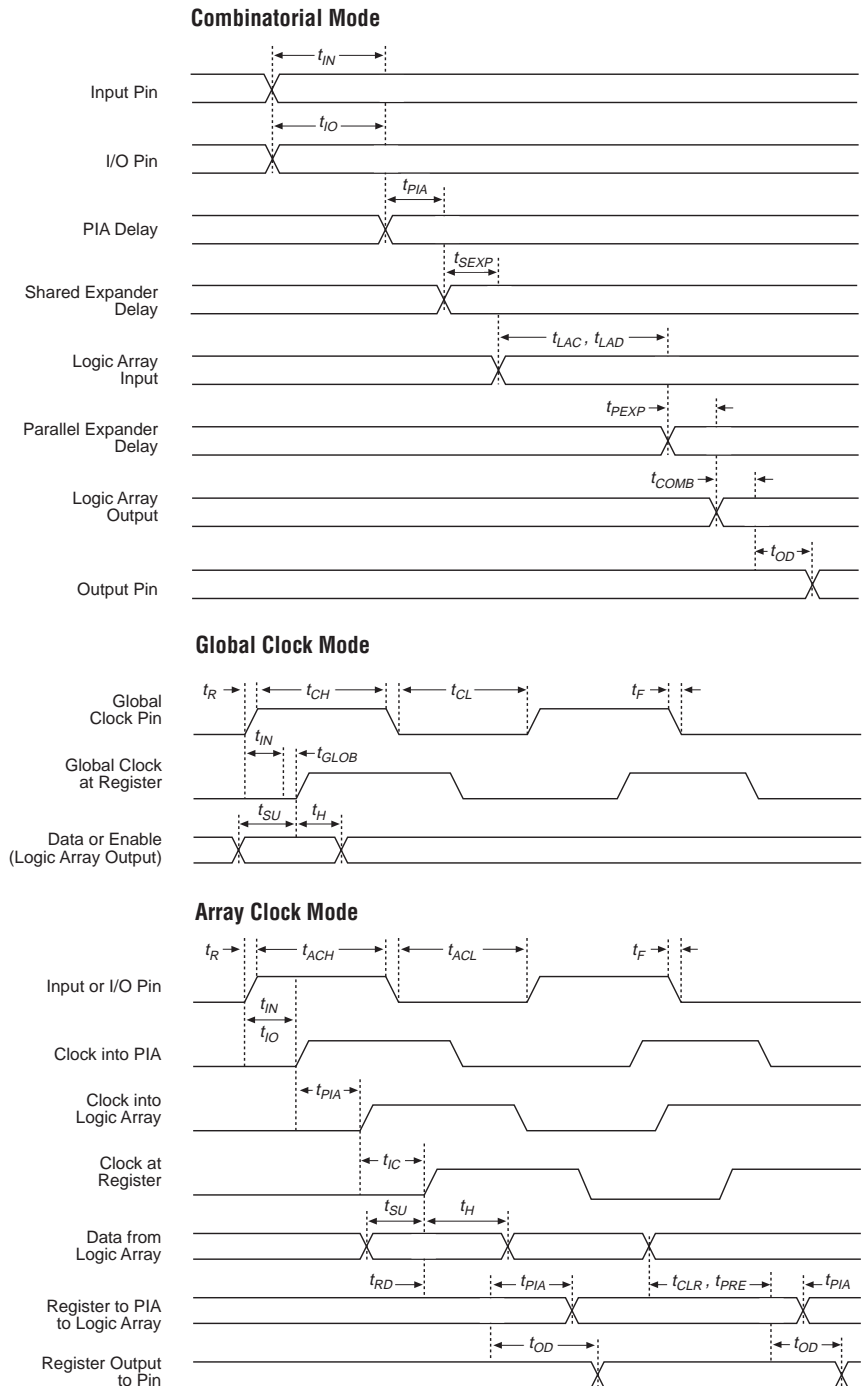
Figure 10. MAX 3000A Timing Model



The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 11 shows the timing relationship between internal and external delay parameters.

Figure 11. MAX 3000A Switching Waveforms

t_R & $t_F < 2$ ns. Inputs are driven at 3 V for a logic high and 0 V for a logic low. All timing characteristics are measured at 1.5 V.



Tables 13 through 20 show EPM3032AE, EPM3064A, EPM3128A, and EPM3256A timing information.

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t_{SU}	Global clock setup time	(2)	2.9		4.7		6.3		ns
t_H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns
t_{CH}	Global clock high time		2.0		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		3.0		4.0		ns
t_{ASU}	Array clock setup time	(2)	1.6		2.5		3.6		ns
t_{AH}	Array clock hold time	(2)	0.3		0.5		0.5		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.4	ns
t_{ACH}	Array clock high time		2.0		3.0		4.0		ns
t_{ACL}	Array clock low time		2.0		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t_{CNT}	Minimum global clock period	(2)		4.4		7.2		9.7	ns
f_{CNT}	Maximum internal global clock frequency	(2), (4)	227.3		138.9		103.1		MHz
t_{ACNT}	Minimum array clock period	(2)		4.4		7.2		9.7	ns
f_{ACNT}	Maximum internal array clock frequency	(2), (4)	227.3		138.9		103.1		MHz

Table 14. EPM3032A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		1.2		1.5	ns
t_{IO}	I/O input pad and buffer delay			0.7		1.2		1.5	ns
t_{SEXP}	Shared expander delay			1.9		3.1		4.0	ns
t_{PEXP}	Parallel expander delay			0.5		0.8		1.0	ns
t_{LAD}	Logic array delay			1.5		2.5		3.3	ns
t_{LAC}	Logic control array delay			0.6		1.0		1.2	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.8		1.3		1.8	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		1.3		1.8		2.3	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.8		6.3		6.8	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.3		2.0		2.8		ns
t_H	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.7		1.2		1.5	ns
t_{COMB}	Combinatorial delay			0.6		1.0		1.3	ns
t_{IC}	Array clock delay			1.2		2.0		2.5	ns
t_{EN}	Register enable time			0.6		1.0		1.2	ns
t_{GLOB}	Global control delay			0.8		1.3		1.9	ns
t_{PRE}	Register preset time			1.2		1.9		2.6	ns
t_{CLR}	Register clear time			1.2		1.9		2.6	ns

Table 14. EPM3032A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PIA}	PIA delay	(2)		0.9		1.5		2.1	ns
t_{LPA}	Low-power adder	(5)		2.5		4.0		5.0	ns

Table 15. EPM3064A External Timing Parameters Note (1)

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10.0	ns
t _{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10.0	ns
t _{SU}	Global clock setup time	(2)	2.8		4.7		6.2		ns
t _H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.1	1.0	5.1	1.0	7.0	ns
t _{CH}	Global clock high time		2.0		3.0		4.0		ns
t _{CL}	Global clock low time		2.0		3.0		4.0		ns
t _{ASU}	Array clock setup time	(2)	1.6		2.6		3.6		ns
t _{AH}	Array clock hold time	(2)	0.3		0.4		0.6		ns
t _{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.6	ns
t _{ACH}	Array clock high time		2.0		3.0		4.0		ns
t _{ACL}	Array clock low time		2.0		3.0		4.0		ns
t _{CPPW}	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t _{CNT}	Minimum global clock period	(2)		4.5		7.4		10.0	ns
f _{CNT}	Maximum internal global clock frequency	(2), (4)	222.2		135.1		100.0		MHz
t _{ACNT}	Minimum array clock period	(2)		4.5		7.4		10.0	ns
f _{ACNT}	Maximum internal array clock frequency	(2), (4)	222.2		135.1		100.0		MHz

Table 16. EPM3064A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.6		1.1		1.4	ns
t_{IO}	I/O input pad and buffer delay			0.6		1.1		1.4	ns
t_{SEXP}	Shared expander delay			1.8		3.0		3.9	ns
t_{PEXP}	Parallel expander delay			0.4		0.7		0.9	ns
t_{LAD}	Logic array delay			1.5		2.5		3.2	ns
t_{LAC}	Logic control array delay			0.6		1.0		1.2	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.8		1.3		1.8	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		1.3		1.8		2.3	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.8		6.3		6.8	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.3		2.0		2.9		ns
t_H	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.7		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.6		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.9		2.5	ns
t_{EN}	Register enable time			0.6		1.0		1.2	ns
t_{GLOB}	Global control delay			1.0		1.5		2.2	ns
t_{PRE}	Register preset time			1.3		2.1		2.9	ns
t_{CLR}	Register clear time			1.3		2.1		2.9	ns

Table 16. EPM3064A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PIA}	PIA delay	(2)		1.0		1.7		2.3	ns
t_{LPA}	Low-power adder	(5)		3.5		4.0		5.0	ns

Table 17. EPM3128A External Timing Parameters Note (1)

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF (2)		5.0		7.5		10	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		5.0		7.5		10	ns
t_{SU}	Global clock setup time	(2)	3.3		4.9		6.6		ns
t_H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.4	1.0	5.0	1.0	6.6	ns
t_{CH}	Global clock high time		2.0		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		3.0		4.0		ns
t_{ASU}	Array clock setup time	(2)	1.8		2.8		3.8		ns
t_{AH}	Array clock hold time	(2)	0.2		0.3		0.4		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	4.9	1.0	7.1	1.0	9.4	ns
t_{ACH}	Array clock high time		2.0		3.0		4.0		ns
t_{ACL}	Array clock low time		2.0		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t_{CNT}	Minimum global clock period	(2)		5.2		7.7		10.2	ns
f_{CNT}	Maximum internal global clock frequency	(2), (4)	192.3		129.9		98.0		MHz
t_{ACNT}	Minimum array clock period	(2)		5.2		7.7		10.2	ns
f_{ACNT}	Maximum internal array clock frequency	(2), (4)	192.3		129.9		98.0		MHz

Table 18. EPM3128A Internal Timing Parameters (Part 1 of 2) Note (1)

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		1.0		1.4	ns
t_{IO}	I/O input pad and buffer delay			0.7		1.0		1.4	ns
t_{SEXP}	Shared expander delay			2.0		2.9		3.8	ns
t_{PEXP}	Parallel expander delay			0.4		0.7		0.9	ns
t_{LAD}	Logic array delay			1.6		2.4		3.1	ns
t_{LAC}	Logic control array delay			0.7		1.0		1.3	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.8		1.2		1.6	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		1.3		1.7		2.1	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.8		6.2		6.6	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.4		2.1		2.9		ns
t_H	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.8		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.5		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.7		2.2	ns
t_{EN}	Register enable time			0.7		1.0		1.3	ns
t_{GLOB}	Global control delay			1.1		1.6		2.0	ns
t_{PRE}	Register preset time			1.4		2.0		2.7	ns
t_{CLR}	Register clear time			1.4		2.0		2.7	ns

Table 18. EPM3128A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PIA}	PIA delay	(2)		1.4		2.0		2.6	ns
t_{LPA}	Low-power adder	(5)		4.0		4.0		5.0	ns

Table 19. EPM3256A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t_{SU}	Global clock setup time	(2)	3.9		5.2		6.9		ns
t_H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.5	1.0	4.8	1.0	6.4	ns
t_{CH}	Global clock high time		2.0		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		3.0		4.0		ns
t_{ASU}	Array clock setup time	(2)	2.0		2.7		3.6		ns
t_{AH}	Array clock hold time	(2)	0.2		0.3		0.5		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	5.4	1.0	7.3	1.0	9.7	ns
t_{ACH}	Array clock high time		2.0		3.0		4.0		ns
t_{ACL}	Array clock low time		2.0		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t_{CNT}	Minimum global clock period	(2)		5.8		7.9		10.5	ns
f_{CNT}	Maximum internal global clock frequency	(2), (4)	172.4		126.6		95.2		MHz
t_{ACNT}	Minimum array clock period	(2)		5.8		7.9		10.5	ns
f_{ACNT}	Maximum internal array clock frequency	(2), (4)	172.4		126.6		95.2		MHz

Table 20. EPM3256A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		0.9		1.2	ns
t_{IO}	I/O input pad and buffer delay			0.7		0.9		1.2	ns
t_{SEXP}	Shared expander delay			2.1		2.8		3.7	ns
t_{PEXP}	Parallel expander delay			0.3		0.5		0.6	ns
t_{LAD}	Logic array delay			1.7		2.2		2.8	ns
t_{LAC}	Logic control array delay			0.8		1.0		1.3	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.2		1.6	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		1.4		1.7		2.1	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.9		6.2		6.6	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.5		2.1		2.9		ns
t_H	Register hold time		0.7		0.9		1.2		ns
t_{RD}	Register delay			0.9		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.5		0.8		1.2	ns
t_{IC}	Array clock delay			1.2		1.6		2.1	ns
t_{EN}	Register enable time			0.8		1.0		1.3	ns
t_{GLOB}	Global control delay			1.0		1.5		2.0	ns
t_{PRE}	Register preset time			1.6		2.3		3.0	ns
t_{CLR}	Register clear time			1.6		2.3		3.0	ns

Table 20. EPM3256A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{PIA}	PIA delay	(2)		1.7		2.4		3.2	ns
t_{LPA}	Low-power adder	(5)		4.0		4.0		5.0	ns

Notes to tables:

- (1) These values are specified in Tables 13 through 20 under the recommended operating conditions shown in Table 9 on page 18.
- (2) These values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (3) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
- (4) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , t_{EXP} , t_{ACL} , and t_{CPW} parameters for macrocells running in low-power mode.

Power Consumption

Supply power (P) versus frequency (f_{MAX} , in MHz) for MAX 3000A devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The P_{IO} value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*.

The I_{CCINT} value depends on the switching frequency and the application logic. The I_{CCINT} value is calculated with the following equation:

$$I_{CCINT} = (A \times MC_{TON}) + [B \times (MC_{DEV} - MC_{TON})] + (C \times MC_{USED} \times f_{MAX} \times \log_{LC})$$

The parameters in the I_{CCINT} equation are:

- MC_{TON} = Number of macrocells with the Turbo Bit™ option turned on, as reported in the MAX+PLUS II Report File (.rpt)
- MC_{DEV} = Number of macrocells in the device
- MC_{USED} = Total number of macrocells in the design, as reported in the RPT File
- f_{MAX} = Highest clock frequency to the device
- to_{GLC} = Average percentage of logic cells toggling at each clock (typically 12.5%)
- A, B, C = Constants (shown in Table 21)

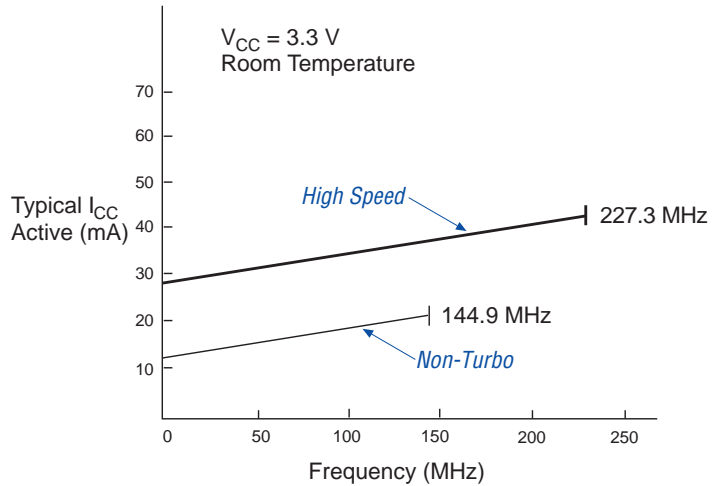
Table 21. MAX 3000A I_{CC} Equation Constants			
Device	A	B	C
EPM3032A	0.85	0.36	0.017
EPM3064A	0.85	0.36	0.017
EPM3128A	0.85	0.36	0.017
EPM3256A	0.85	0.36	0.017

The I_{CCINT} calculation provides an I_{CC} estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual I_{CC} should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

Figures 12 and 13 shows the typical supply current versus frequency for MAX 3000A devices.

Figure 12. I_{CC} vs. Frequency for MAX 3000A Devices (Part 1 of 2)

EPM3032A



EPM3064A

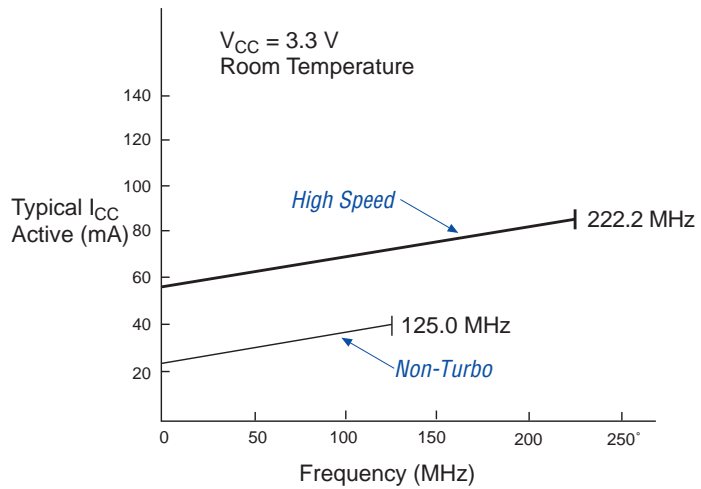
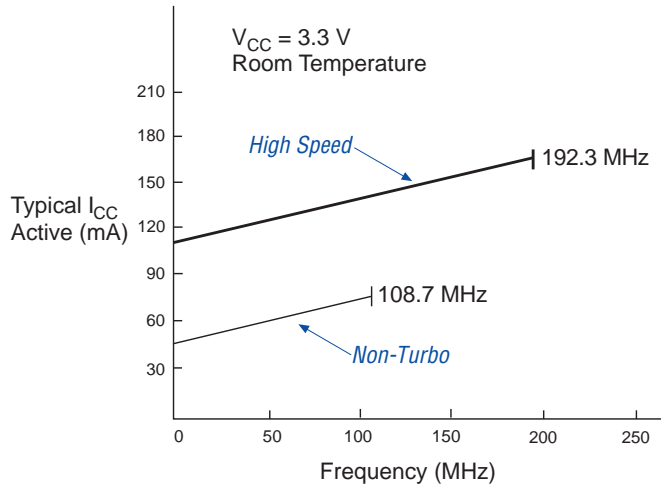
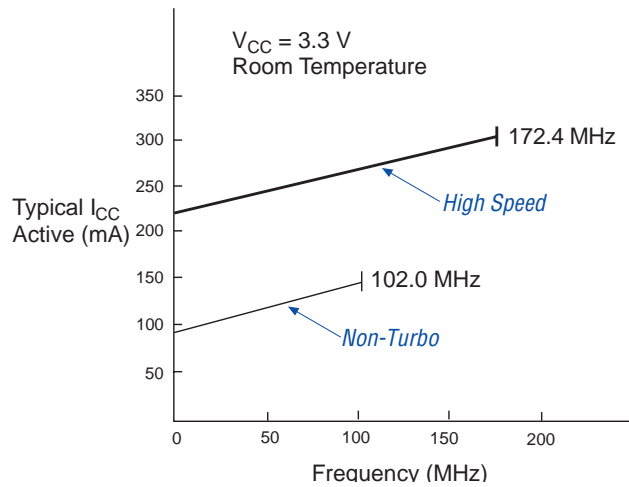


Figure 13. I_{CC} vs. Frequency for MAX 3000A Devices (Part 2 of 2)

EPM3128A



EPM3256A



Device Pin-Outs

Tables 22 through 29 show the pin names and numbers for the pins in MAX 3000A device packages.

Dedicated Pin	44-Pin PLCC	44-Pin TQFP
INPUT/GCLK1	43	37
INPUT/GCLR _n	1	39
INPUT/OE1	44	38
INPUT/OE2/GCLK2	2	40
TDI (1)	7	1
TMS (1)	13	7
TCK (1)	32	26
TDO (1)	38	32
GNDINT	22, 42	16, 36
GNDIO	10, 17, 30, 36	4, 11, 24, 30
VCCINT (3.3 V)	3, 23	17, 41
VCCIO (2.5 V or 3.3 V)	15, 35	9, 29
No Connect (N.C.)	–	–
Total User I/O Pins (2)	34	34

Table 23. EPM3032A I/O Pin-Outs

LAB	MC	44-Pin PLCC	44-Pin TQFP	LAB	MC	44-Pin PLCC	44-Pin TQFP
A	1	4	42	B	17	41	35
	2	5	43		18	40	34
	3	6	44		19	39	33
	4	7 (1)	1 (1)		20	38 (1)	32 (1)
	5	8	2		21	37	31
	6	9	3		22	–	–
	7	11	5		23	34	28
	8	12	6		24	33	27
	9	13 (1)	7 (1)		25	32 (1)	26 (1)
	10	14	8		26	31	25
	11	16	10		27	29	23
	12	–	–		28	28	22
	13	18	12		29	27	21
	14	19	13		30	26	20
	15	20	14		31	25	19
	16	21	15		32	24	18

Notes to tables:

- (1) This pin may function as either a JTAG port or a user I/O pin. When the device is configured to use the JTAG ports for in-system programming, this pin is not available as a user I/O pin.
- (2) The user I/O pin count includes dedicated input pins and all I/O pins.

Table 24. EPM3064A Dedicated Pin-Outs			
Dedicated Pin	44-Pin PLCC	44-Pin TQFP	100-Pin TQFP
INPUT/GCLK1	43	37	87
INPUT/GCLRn	1	39	89
INPUT/OE1	44	38	88
INPUT/OE2/GCLK2	2	40	90
TDI (1)	7	1	4
TMS (1)	13	7	15
TCK (1)	32	26	62
TDO (1)	38	32	73
GNDINT	22, 42	16, 36	38, 86
GNDIO	10, 17, 30, 36	4, 11, 24, 30	11, 26, 33, 43, 53, 59, 65, 74, 78, 95
VCCINT (3.3 V Only)	3, 23	17, 41	39, 91
VCCIO (2.5 V or 3.3 V)	15, 35	9, 29	3, 18, 34, 51, 66, 82
No Connect (N.C.)	–	–	1, 2, 5, 7, 22, 24, 27, 28, 49, 50, 55, 70, 72, 77
Total User I/O Pins (2)	34	34	66

Table 25. EPM3064A I/O Pin-Outs

LAB	MC	44-Pin PLCC	44-Pin TQFP	100-Pin TQFP	LAB	MC	44-Pin PLCC	44-Pin TQFP	100-Pin TQFP
A	1	12	6	14	C	33	24	18	40
	2	–	–	13		34	–	–	41
	3	11	5	12		35	25	19	42
	4	9	3	10		36	26	20	44
	5	8	2	9		37	27	21	45
	6	–	–	8		38	–	–	46
	7	–	–	6		39	–	–	47
	8	7 (1)	1 (1)	4 (1)		40	28	22	48
	9	–	–	100		41	29	23	52
	10	–	–	99		42	–	–	54
	11	6	44	98		43	–	–	56
	12	–	–	97		44	–	–	57
	13	–	–	96		45	–	–	58
	14	5	43	94		46	31	25	60
	15	–	–	93		47	–	–	61
	16	4	42	92		48	32 (1)	26 (1)	62 (1)
B	17	21	15	37	D	49	33	27	63
	18	–	–	36		50	–	–	64
	19	20	14	35		51	34	28	–
	20	19	13	–		52	–	–	67
	21	18	12	32		53	37	31	68
	22	–	–	31		54	–	–	69
	23	–	–	30		55	–	–	71
	24	–	–	29		56	38 (1)	32 (1)	73 (1)
	25	16	10	25		57	39	33	75
	26	–	–	23		58	–	–	76
	27	–	–	21		59	–	–	79
	28	–	–	20		60	–	–	80
	29	–	–	19		61	–	–	81
	30	14	8	17		62	40	34	83
	31	–	–	16		63	–	–	84
	32	13 (1)	7 (1)	15 (1)		64	41	35	85

Notes to tables:

- (1) This pin may function as either a JTAG port or a user I/O pin. When the device is configured to use the JTAG ports for in-system programming, this pin is not available as a user I/O pin.
- (2) The user I/O pin count includes dedicated input pins and all I/O pins.

Table 26. EPM3128A Dedicated Pin-Outs

Dedicated Pin	100-Pin TQFP	144-Pin TQFP
INPUT/GCLK1	87	125
INPUT/GCLRn	89	127
INPUT/OE1	88	126
INPUT/OE2/GCLK2	90	128
TDI (1)	4	4
TMS (1)	15	20
TCK (1)	62	89
TDO (1)	73	104
GNDINT	38, 86	52, 57, 124, 129
GNDIO	11, 26, 33, 43, 53, 59, 65, 74, 78, 95	3, 13, 17, 26, 33, 59, 64, 77, 85, 94, 105, 114, 135
VCCINT (3.3 V Only)	39, 91	51, 58, 123, 130
VCCIO (2.5 V or 3.3 V)	3, 18, 34, 51, 66, 82	24, 50, 73, 76, 95, 115, 144
No Connect (N.C.)	–	1, 2, 12, 19, 34, 35, 36, 43, 46, 47, 48, 49, 66, 75, 90, 103, 108, 120, 121, 122
Total User I/O Pins (2)	80	96

Table 27. EPM3128A I/O Pin-Outs (Part 1 of 2)

LAB	MC	100-Pin TQFP	144-Pin TQFP	LAB	MC	100-Pin TQFP	144-Pin TQFP
A	1	2	143	C	33	25	32
	2	–	–		34	–	–
	3	1	142		35	24	31
	4	–	141		36	–	30
	5	100	140		37	23	29
	6	99	139		38	22	28
	7	–	–		39	–	–
	8	98	138		40	21	27
	9	97	137		41	20	–
	10	–	–		42	–	–
	11	96	136		43	19	25
	12	–	134		44	–	23
	13	94	133		45	17	22
	14	93	132		46	16	21
	15	–	–		47	–	–
	16	92	131		48	15 (1)	20 (1)
B	17	14	18	D	49	37	56
	18	–	–		50	–	–
	19	13	16		51	36	55
	20	–	15		52	–	54
	21	12	14		53	35	53
	22	10	11		54	–	45
	23	–	–		55	–	–
	24	9	10		56	32	44
	25	8	9		57	31	42
	26	–	–		58	–	–
	27	7	8		59	30	41
	28	–	7		60	–	40
	29	6	6		61	29	39
	30	5	5		62	28	38
	31	–	–		63	–	–
	32	4 (1)	4 (1)		64	27	37

Table 27. EPM3128A I/O Pin-Outs (Part 2 of 2)

LAB	MC	100-Pin TQFP	144-Pin TQFP	LAB	MC	100-Pin TQFP	144-Pin TQFP
E	65	40	60	G	97	63	91
	66	–	–		98	–	–
	67	41	61		99	64	92
	68	–	62		100	–	93
	69	42	63		101	–	–
	70	44	65		102	67	96
	71	–	–		103	–	–
	72	45	67		104	68	97
	73	46	68		105	69	98
	74	–	–		106	–	–
	75	47	69		107	70	99
	76	–	70		108	–	100
	77	48	71		109	71	101
	78	49	72		110	72	102
	79	–	–		111	–	–
80	50	74	112	73 (1)	104 (1)		
F	81	52	–	H	113	75	106
	82	–	–		114	–	–
	83	–	78		115	76	107
	84	–	79		116	–	109
	85	54	80		117	77	110
	86	55	81		118	–	111
	87	–	–		119	–	–
	88	56	82		120	79	112
	89	57	83		121	80	113
	90	–	–		122	–	–
	91	58	84		123	81	–
	92	–	86		124	–	116
	93	60	87		125	83	117
	94	61	88		126	84	118
	95	–	–		127	–	–
96	62 (1)	89 (1)	128	85	119		

Notes to tables:

- (1) This pin may function as either a JTAG port or a user I/O pin. When the device is configured to use the JTAG ports for in-system programming, this pin is not available as a user I/O pin.
- (2) The user I/O pin count includes dedicated input pins and all I/O pins.

Dedicated Pin	144-Pin TQFP	208-Pin PQFP
INPUT/GCLK1	125	184
INPUT/GCLRn	127	182
INPUT/OE1	126	183
INPUT/OE2/GCLK2	128	181
TDI (1)	4	176
TMS (1)	20	127
TCK (1)	89	30
TDO (1)	104	189
GNDINT	52, 57, 124, 129	75, 82, 180, 185
GNDIO	3, 13, 17, 26, 33, 59, 64, 77, 85, 94, 105, 114, 135	6, 14, 32, 40, 50, 72, 84, 94, 108, 116, 134, 142, 152, 174, 190, 200
VCCINT (3.3 V Only)	51, 58, 123, 130	74, 83, 179, 186
VCCIO (2.5 V or 3.3 V)	24, 50, 73, 76, 95, 115, 144	5, 23, 41, 63, 85, 107, 125, 143, 165, 191
No Connect (N.C.)	–	1, 2, 51, 52, 53, 54, 103, 104, 105, 106, 155, 156, 157, 158, 207, 208
Total User I/O Pins (2)	116	158

Table 29. EPM3256A I/O Pin-Outs (Part 1 of 4)

LAB	MC	144-Pin TQFP	208-Pin PQFP	LAB	MC	144-Pin TQFP	208-Pin PQFP
A	1	–	153	C	33	36	–
	2	–	–		34	–	–
	3	2	154		35	35	109
	4	–	–		36	–	–
	5	1	159		37	34	110
	6	143	160		38	–	111
	7	–	–		39	–	–
	8	–	161		40	32	112
	9	–	162		41	31	113
	10	–	–		42	–	–
	11	142	163		43	30	114
	12	–	–		44	–	–
	13	141	164		45	29	115
	14	140	166		46	–	117
	15	–	–		47	–	–
	16	139	167		48	28	118
B	17	–	141	D	49	44	92
	18	–	–		50	–	–
	19	10	–		51	43	93
	20	–	–		52	–	–
	21	9	144		53	42	95
	22	–	145		54	41	96
	23	–	–		55	–	–
	24	8	146		56	40	97
	25	7	147		57	–	98
	26	–	–		58	–	–
	27	6	148		59	39	99
	28	–	–		60	–	–
	29	5	149		61	38	100
	30	–	150		62	–	101
	31	–	–		63	–	–
	32	4 (1)	151		64	37	102

Table 29. EPM3256A I/O Pin-Outs (Part 2 of 4)

LAB	MC	144-Pin TQFP	208-Pin PQFP	LAB	MC	144-Pin TQFP	208-Pin PQFP
E	65	–	168	G	97	–	119
	66	–	–		98	–	–
	67	–	169		99	27	120
	68	–	–		100	–	–
	69	138	170		101	–	121
	70	–	171		102	–	122
	71	–	–		103	–	–
	72	137	172		104	25	123
	73	136	173		105	23	124
	74	–	–		106	–	–
	75	134	175		107	22	126
	76	–	–		108	–	–
	77	133	176 (1)		109	21	127 (1)
	78	132	177		110	–	128
	79	–	–		111	–	–
80	131	178	112	20 (1)	129		
F	81	–	130	H	113	–	79
	82	–	–		114	–	–
	83	19	131		115	54	80
	84	–	–		116	–	–
	85	18	132		117	53	81
	86	–	133		118	–	–
	87	–	–		119	–	–
	88	16	135		120	49	86
	89	15	136		121	48	87
	90	–	–		122	–	–
	91	14	137		123	47	88
	92	–	–		124	–	–
	93	12	138		125	46	89
	94	–	139		126	–	90
	95	–	–		127	–	–
96	11	140	128	45	91		

Table 29. EPM3256A I/O Pin-Outs (Part 3 of 4)

LAB	MC	144-Pin TQFP	208-Pin PQFP	LAB	MC	144-Pin TQFP	208-Pin PQFP
I	129	–	197	K	161	–	38
	130	–	–		162	–	–
	131	116	196		163	82	37
	132	–	–		164	–	–
	133	117	195		165	83	36
	134	–	194		166	–	35
	135	–	–		167	–	–
	136	118	193		168	84	34
	137	119	192		169	86	33
	138	–	–		170	–	–
	139	120	–		171	87	31
	140	–	–		172	–	–
	141	121	189 (1)		173	88	30 (1)
	142	–	188		174	–	29
	143	–	–		175	–	–
144	122	187	176	89 (1)	28		
J	145	–	27	L	177	–	78
	146	–	–		178	–	–
	147	90	26		179	55	77
	148	–	–		180	–	–
	149	91	25		181	56	76
	150	–	24		182	–	73
	151	–	–		183	–	–
	152	92	22		184	60	71
	153	93	21		185	61	70
	154	–	–		186	–	–
	155	–	20		187	62	69
	156	–	–		188	–	–
	157	96	19		189	63	68
	158	–	18		190	–	67
	159	–	–		191	–	–
	160	97	17		192	65	66

Table 29. EPM3256A I/O Pin-Outs (Part 4 of 4)

LAB	MC	144-Pin TQFP	208-Pin PQFP	LAB	MC	144-Pin TQFP	208-Pin PQFP
M	193	106	4	O	225	–	49
	194	–	–		226	–	–
	195	107	3		227	74	48
	196	–	–		228	–	–
	197	108	206		229	75	47
	198	–	205		230	–	46
	199	–	–		231	–	–
	200	109	204		232	–	45
	201	110	203		233	78	44
	202	–	–		234	–	–
	203	111	202		235	79	43
	204	–	–		236	–	–
	205	–	201		237	80	42
	206	112	199		238	–	–
	207	–	–		239	–	–
	208	113	198		240	81	39
N	209	–	16	P	241	66	65
	210	–	–		242	–	–
	211	98	15		243	67	64
	212	–	–		244	–	–
	213	99	13		245	68	62
	214	–	12		246	69	61
	215	–	–		247	–	–
	216	100	11		248	–	60
	217	101	10		249	70	59
	218	–	–		250	–	–
	219	102	9		251	–	58
	220	–	–		252	–	–
	221	103	8		253	71	57
	222	–	7		254	–	56
	223	–	–		255	–	–
	224	104 (1)	–		256	72	55

Notes to tables:

- (1) This pin can function as either a JTAG pin or a user I/O pin. When the device is programmed to use the JTAG ports for boundary-scan testing or in-system programming, this pin is not available as a user I/O pin.
- (2) The user I/O pin count includes dedicated input pins and all I/O pins.

Figures 14 through 17 show the package pin-out diagrams for MAX 3000A devices.

Figure 14. 44-Pin PLCC/TQFP Package Pin-Out Diagram

Package outlines not drawn to scale.

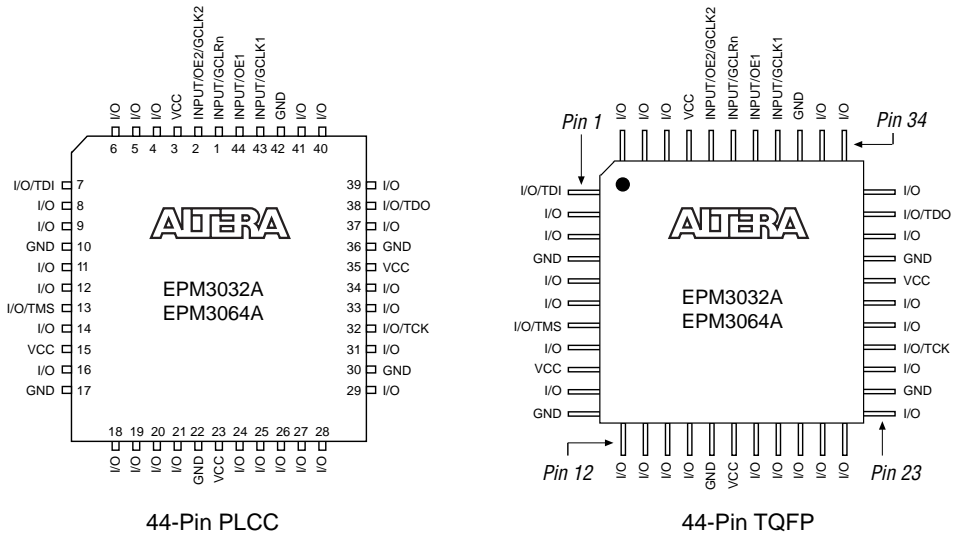


Figure 15. 100-Pin TQFP Package Pin-Out Diagram

Package outline not drawn to scale.

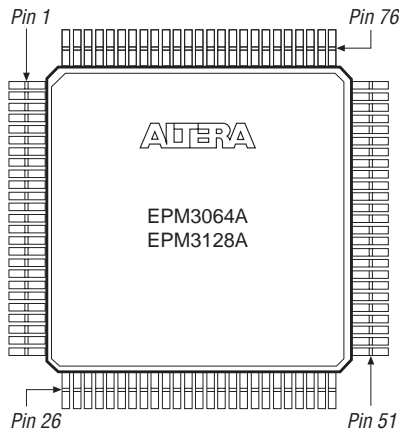


Figure 16. 144-Pin TQFP Package Pin-Out Diagram

Package outline not drawn to scale.

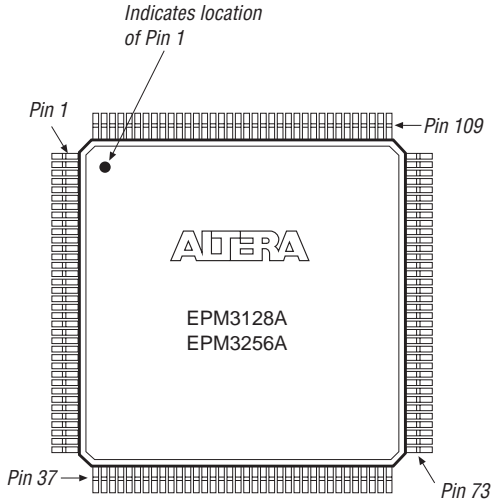
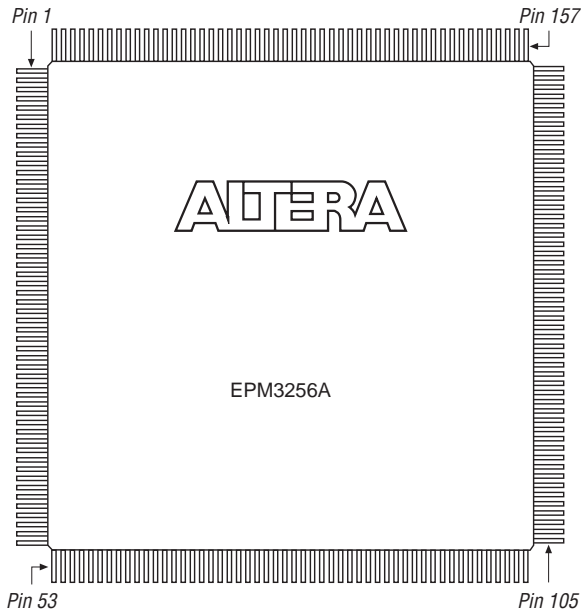


Figure 17. 208-Pin PQFP Package Pin-Out Diagram

Package outline not drawn to scale.



Revision History

The information contained in the *MAX 3000A Programmable Logic Device Family Data Sheet* version 1.1 supersedes information published in previous versions.

Version 1.1 Changes

MAX 3000A Programmable Logic Device Family Data Sheet version 1.1 contains the following changes:

- Made minor style and textual changes
- Updated timing values in Table 1 and Tables 13 through 20
- Updated Table 2 and Note (1)
- Removed Quartus™ information throughout the document
- Updated Notes to Table 10
- Updated drive characteristics in Figure 9
- Updated ICC current constants in Table 21 and Figures 12 and 13

Version 1.01 Changes

MAX 3000A Programmable Logic Device Family Data Sheet version 1.01 contains the following changes:

- Corrected Figure 2
- Corrected notes in Tables 10 and 11
- Corrected the maximum V_{OL} value for 3.3-V low-level TTL output voltage in Table 11
- Added the t_{CPW} parameter to Tables 13 and 15
- Updated Table 21
- Updated Figure 12
- Corrected total I/O count for EPM3064A devices in 100-pin TQFP packages in Tables 3 and 24



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